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 TITLE: Segmented architecture for wafer test and burn-in

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6 US 6357025 B1		USPAT	20020312	11 Tes
7 US 6349396 B1		USPAT	20020219	18 Tes
8 US 6340895 B1		USPAT	20020122	34 Waf
9 US 6340838 B1		USPAT	20020122	11 App
10 US 6320397 B1		USPAT	20011120	13 Mol
11 US 6297658 B1		USPAT	20011002	19 Waf
12 US 6275051 B1		USPAT	20010814	35 Seg

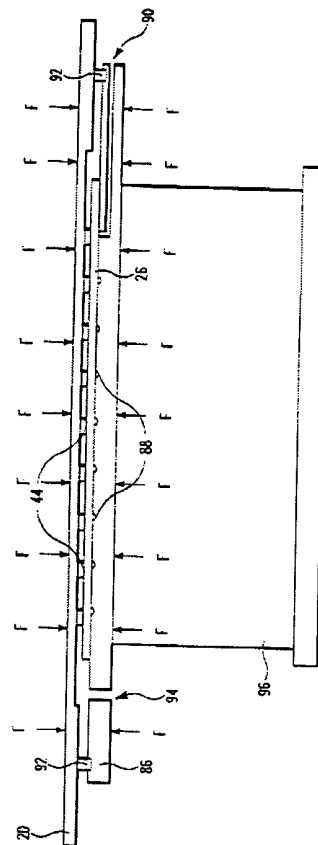


FIG. 7b